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Factory Control

- Development of a Perfectly Balanced Electrostatic Eliminator Utilizing an Intermittent Pulse AC Voltage Power Supply
- Analysis of Pulsed DC Ionizer Measurement Procedures with a CPM Using ESDA RP 3.11-2006
- Manufacturing Changes Air Ionization Technology
- A Novel New Concept in Hybrid Alpha Ionization Systems

System Level ESD Design

- Innovative High Density ESD Protection Device in State of the Art FDSOI UTBB Technologies
- Design and Optimization of ESD Lateral NPN Device in 14nm FinFET SOI CMOS Technology
- VFTLP Characteristics of ESD Protection Diodes in Advanced Bulk FinFET Technology
- ESD Characterization of Germanium FinFET Diodes and ggMOS
- An Electrostatic-Discharge-Protection Solution for Silicon-Carbide MESFET
- Self-ESD-Protected Transmission Line Broadband in CMOS28nm UTBB-FDSOI
- CDM-Reliable T-coil Techniques for High-Speed Wireline Receivers
- Robust ESD Clamp for Envelop Tracking Power Supply
- Practical Methodology for Extraction of SEED Models
- ESD Induced Functional Upset in Magnetic Sensor ICs
- Secondary Discharge – A Potential Risk during System Level HBM ESD Testing
- A Passive Coupling Circuit for Injecting TLP-Like Stress Pulses into only one End of a Driver/Receiver System
- Essential – Integration of ESD Verification Methodologies
- Schematic-Level and Layout-Level ESD EDA Check Methodology Applied to Smart Power IC's – Initialization and Implementation
- A Comprehensive ESD Verification Flow at Transistor Level for Large SoC Designs
- HBM Failures Induced by Circuit Interaction with ESD Cell Behavior
- Soft Fails Due to LU Stress of Virtual Power Domains
- ESD Failure Caused by Parasitic SCR in an Overvoltage Tolerant I/O

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